

**AMENDMENTS TO SPECIFICATION**

Rewrite the paragraph beginning on page 14, line 16, as follows:

In some cases, a slight amount of force may be undesirably applied to a semiconductor chip when the semiconductor chip is mounted on a package. This may cause a property of the monitor transistor (MOS transistor) to fluctuate (change), for example, the threshold of the voltage of the MOS transistor. The degree of such change is greater toward the periphery of the semiconductor chip than the center portion of the semiconductor chip. Therefore, as shown in Figs. 3 and 4, by disposing the multiple PMOS transistors Q1-Q4 at the periphery of the area AM1 of the driver transistor M1 or within the area of the area AM1 of the driver transistor M1, the fluctuation (changes) in a property of the monitor transistor (MOS transistor) M11, which is caused when force is applied to the semiconductor chip, can be averaged (balanced). Accordingly, the property of the driver transistor M1 can be matched with the property of the monitor transistor M11.